Se	Search Notes	

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/749,418	TOKARSI ET AL.	
Examiner	Art Unit	
Christopher PoDee	1756	

SEARCHED			
Class	Subclass	Date	Examiner
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399	159	9/22/2005	CDR
548	444 416	9/22/2005	CDR
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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	DATE	EXMR
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